

BoHS COMPLIANT

HALOGEN FREE

### SI7106DN-T1-E3-VB Datasheet

## N-Channel 20 V (D-S) MOSFET

**FEATURES** 

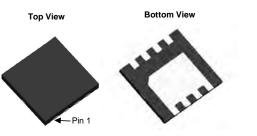
• Trench power MOSFET 100 % R<sub>g</sub> and UIS tested

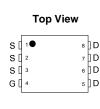
• High power density DC/DC • Synchronous rectification Embedded DC/DC

**APPLICATIONS** 

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (TYP.)			
20	0.0055 at V <sub>GS</sub> = 4.5V	58	9.4 nC			
20	0.0057 at V <sub>GS</sub> = 2.5 V	45	3.4110			

#### DFN 3x3 EP





# GC S

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (	T <sub>A</sub> = 25 °C, unless	s otherwise noted	(k	
PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V <sub>DS</sub>	20	V	
Gate-Source Voltage		V <sub>GS</sub>	+12	v
	T <sub>C</sub> = 25 °C		58	
Continuous Drain Current (T 150 °C)	T <sub>C</sub> = 70 °C		46	
Continuous Drain Current ( $T_J = 150 \ ^{\circ}C$ )	T <sub>A</sub> = 25 °C	I <sub>D</sub>	19.8 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		15.8 <sup>b, c</sup>	A
Pulsed Drain Current (t = 300 µs)	I <sub>DM</sub>	150	A	
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	1	14.1	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	3.2 <sup>b, c</sup>	
Single Pulse Avalanche Current		I <sub>AS</sub>	15	
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	11.25	mJ
	T <sub>C</sub> = 25 °C		31.2	
Maximum Dawar Dissinction	T <sub>C</sub> = 70 °C		20	w
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.6 <sup>b, c</sup>	vv
	T <sub>A</sub> = 70 °C		2.3 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	℃
Soldering Recommendations (Peak Temperature		260	U U	

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT	
Maximum Junction-to-Ambient <sup>b, f</sup>	t ≤ 10 s	R <sub>thJA</sub>	24	34	°C/W	
Maximum Junction-to-Case (Drain)	Steady State R <sub>thJC</sub> 3 4		0/10			

Notes

a. Based on  $T_C = 25$  °C.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. The DFN3X3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.

f. Maximum under steady state conditions is 70 °C/W.

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = 250 \mu A$	20	-	-		
Drain-Source Breakdown Voltage (transient) c	V <sub>DSt</sub>	$V_{GS} = 0 \text{ V}, \text{ I}_{D(aval)} = 15 \text{ A}, \text{ t}_{transient} = 50 \text{ ns}$	26	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_J$			20	-	mV/°	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA	-	-4.6	-	С	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	0.5	-	1.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = 12V$	-	-	± 100	nA	
Zaus Oata Maltana Dusia Orimont	I <sub>DSS</sub>	$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	1	μΑ	
Zero Gate Voltage Drain Current		$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 ^{\circ}\text{C}$	-	-	10		
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	30	-	-	А	
Durin Course On Otata Desistance 3		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 10 \text{ A}$	-	0.0055	-	Ω	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 2.5 \text{ V}, \text{ I}_{D} = 8 \text{ A}$	-	0.0057	-		
Forward Transconductance <sup>a</sup>	<b>g</b> <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 10 A	-	65	-	S	
Dynamic <sup>b</sup>							
Input Capacitance	Ciss		-	1450	-		
Output Capacitance	Coss		-	445	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		38	-	- pF	
C <sub>rss</sub> /C <sub>iss</sub> Ratio				0.026	0.052		
Tatal Oata Ohavaa	Qg	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	19.4	29	nC	
Total Gate Charge			-	9.4	14		
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$	-	4	-		
Gate-Drain Charge	Q <sub>gd</sub>		-	1.8	-		
Output Charge	Q <sub>oss</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}$	-	12.5	-		
Gate Resistance	Rg	f = 1 MHz	0.4	1.65	3.3	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>		-	9	18		
Rise Time	t <sub>r</sub>	$\label{eq:VDD} \begin{array}{c} V_{DD} = 15 \text{ V},  \text{R}_{\text{L}} = 1.5 \ \Omega \\ \text{I}_{\text{D}} \cong 10 \text{ A},  \text{V}_{\text{GEN}} = 10 \text{ V},  \text{R}_{\text{g}} = 1 \ \Omega \end{array}$		8	16		
Turn-Off Delay Time	t <sub>d(off)</sub>			18	36		
Fall Time	t <sub>f</sub>		-	8	16	- 	
Turn-On Delay Time	t <sub>d(on)</sub>		-	15	30	- ns	
Rise Time	t <sub>r</sub>	$V_{DD} = 15 \text{ V}, \text{ R}_{\text{L}} = 1.5 \Omega$	-	12	24		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 10 \text{ A}, V_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_g = 1 \Omega$		18	36	-	
Fall Time	t <sub>f</sub>			9	18		
Drain-Source Body Diode Characteristics		· · ·					
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C	-	-	14.1	^	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>		-	-	80	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 3 A	-	0.76	1.1	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	24	48	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 10 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C		14	28	nC	
Reverse Recovery Fall Time	t <sub>a</sub>			12	-	ns	
Reverse Recovery Rise Time	t <sub>b</sub>			12	-		

#### Notes

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

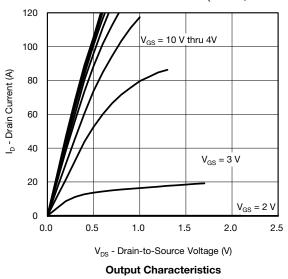
b. Guaranteed by design, not subject to production testing.

c. T<sub>CASE</sub> = 25 °C. Expected voltage stress during 100 % UIS test. Production datalog is not available.

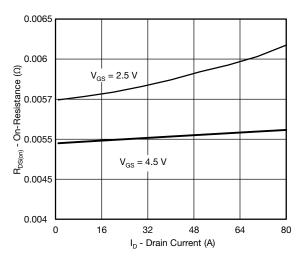
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

emi

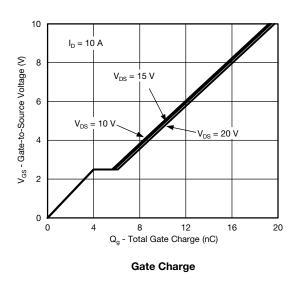


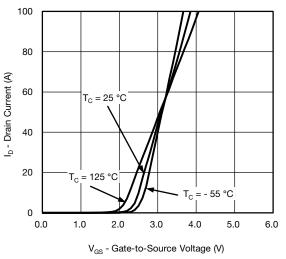


#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

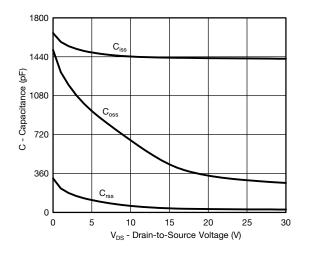


**On-Resistance vs. Drain Current** 

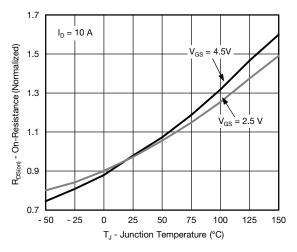




Transfer Characteristics

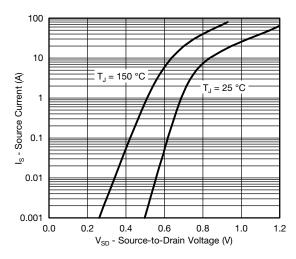






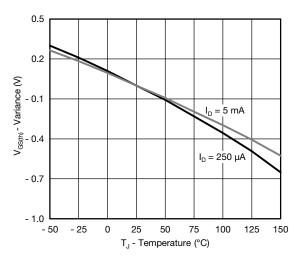




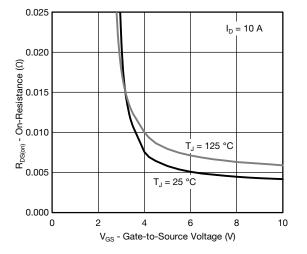


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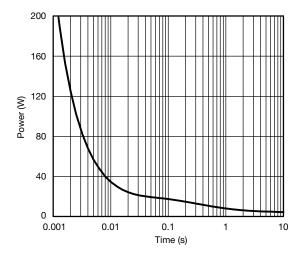




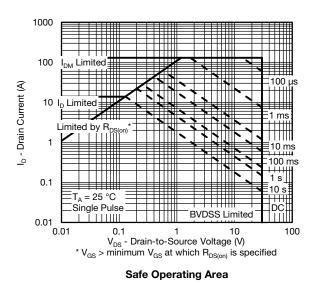




On-Resistance vs. Gate-to-Source Voltage

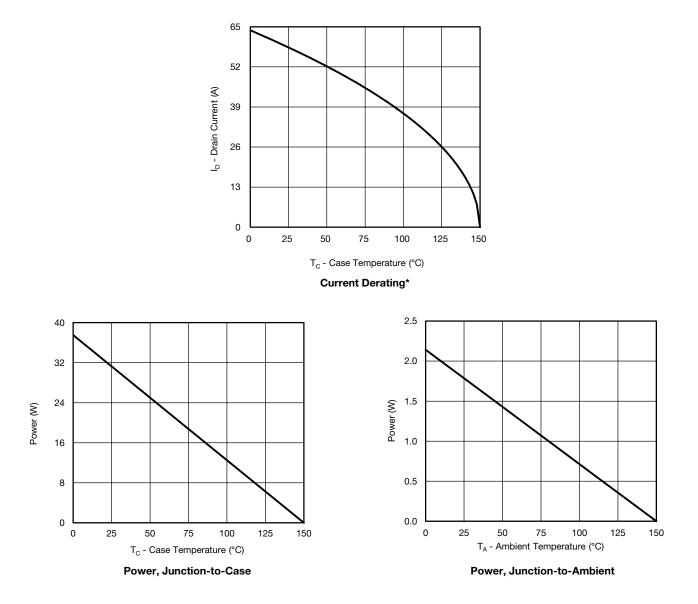


Single Pulse Power, Junction-to-Ambient





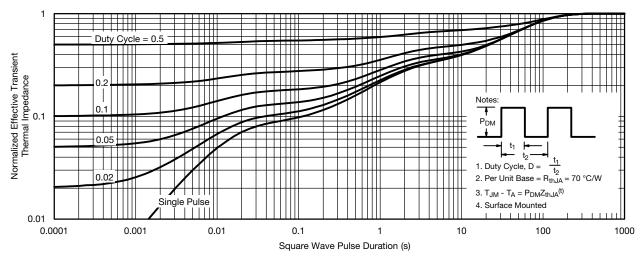
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



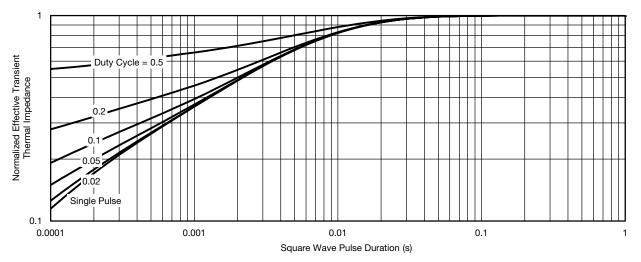
\* The power dissipation  $P_D$  is based on  $T_{J (max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





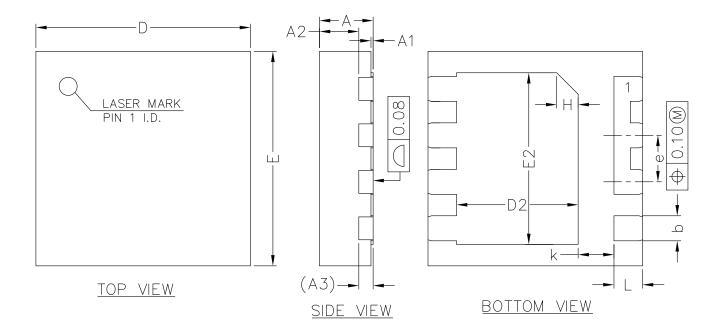


Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case







<u>SIDE VIEW</u>

SYMBOL	MIN	NOM	МАХ			
А	0.70	0.75	0.80			
A1	0.00	0.02	0.05			
A2	0.50	0.55	0.60			
A3	0.20REF					
b	0.30	0.35	0.40			
D	2.90	3.00	3.10			
E	2.90	3.00	3.10			
D2	1.60	1.70	1.80			
E2	2.30	2.40	2.50			
е	0.55	0.65	0.75			
К	0.40	0.50	0.60			
L	0.35	0.40	0.45			

# COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)



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